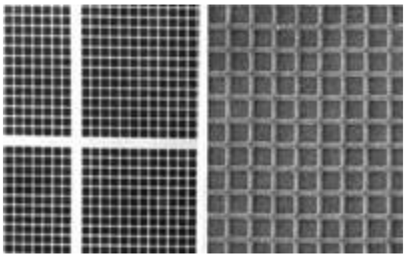
Technical Data Sheet

Silicone Test Specimen

#79502



The test specimen consists of lines etched into a single crystal silicon substrate, written by electron beam machinery. It consists of a square mesh of course lines of 500µm spacing with 50 intermediate fine lines of 10µm spacings.

The 10µm pitch has been measured using an automatic line width measuring system.

Position	Pitch Meas. µm
1	10.004
2	9.997
3	9.989
	10.004
5	9.997
6	9.988
7	9.982
8	10.001
9	9.969
10	9.953
11	9.975
12	9.986
13	9.944

Measurement Stats

Max	10.004
Min	9.944
Mean	9.984
Standard Deviation	0.02